Signal and Image Processing Based on Machine/Deep Learning Techniques

Guest Editors:

Dr. Omneya Attallah
Department of Electronics and Communications Engineering, College of Engineering and Technology, Arab Academy for Science, Technology and Maritime Transport, P.O. Box 1029, Alexandria, Egypt

Dr. Kadir Sabancı
Department of Electrical and Electronics Engineering, Karamanoglu Mehmetbey University, Karaman 70100, Turkey

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Message from the Guest Editors

This Special Issue aims to collect articles describing the contributions of ML and DL technologies to the development of advanced signal processing and image processing for various applications. Include but are not limited to the following: 1) Machine and deep learning for signal and image/video processing; 2) Advanced computational intelligence for signal and image presentation; 3) Deep learning vs. traditional machine learning comparative analysis of signals and images; 4) Reviews of different machine and deep learning for signals and images; 5) Machine and deep learning in biomedical signal and medical image processing; 6) Machine and deep learning for medical and health informatics; 7) Computational intelligence for big data; 8) Multimodal learning algorithms for signal and image processing; 9) Machine and deep learning for fault diagnosis and proactive maintenance; 10) Signal and image transformations using machine learning and deep learning; 11) Machine and deep learning for automatic detection and segmentation; 12) Machine and deep learning for ambient intelligence and assistive living; 13) Machine and deep learning for human activity and motion recognition.

Special Issue

Editor-in-Chief

Prof. Dr. Giulio Nicola Cerullo
Dipartimento di Fisica,
Politecnico di Milano, Piazza L.
da Vinci 32, 20133 Milano, Italy

Message from the Editor-in-Chief

As the world of science becomes ever more specialized, researchers may lose themselves in the deep forest of the ever increasing number of subfields being created. This open access journal Applied Sciences has been started to link these subfields, so researchers can cut through the forest and see the surrounding, or quite distant fields and subfields to help develop his/her own research even further with the aid of this multi-dimensional network.

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